INTEGRATED CIRCUITS

DATA SHEET

74LV2598-bit addressable latch

Product specification Supersedes data of 1997 Jun 06 IC24 Data Handbook





8-bit addressable latch

74LV259

FEATURES

- Optimized for low voltage applications: 1.0 to 3.6 V
- \bullet Accepts TTL input levels between $V_{CC} = 2.7 \text{ V}$ and $V_{CC} = 3.6 \text{ V}$
- Typical V_{OLP} (output ground bounce) < 0.8 V at V_{CC} = 3.3 V, $T_{amb} = 25^{\circ}C$
- Typical V_{OHV} (output V_{OH} undershoot) > 2 V at V_{CC} = 3.3 V, $T_{amb} = 25^{\circ}C$
- Combines demultiplexer and 8-bit latch
- Serial-to-parallel capability
- Output from each storage bit available
- Random (addressable) data entry
- Easily expandable
- Common reset input
- Useful as a 3-to-8 active HIGH decoder
- Output capability: standard
- I_{CC} category: MSI

DESCRIPTION

The 74LV259 is a low-voltage CMOS device and is pin and function compatible with 74HC/HCT259.

The 74LV259 is a high-speed 8-bit addressable latch designed for general purpose storage applications in digital systems. The 74LV259 is a multifunction device capable of storing single-line data in eight addressable latches, and also 3-to-8 decoder and demultiplexer, with active HIGH outputs (Q₀ to Q₇), functions are available. The 74LV259 also incorporate an active LOW common reset (MR) for resetting all latches, as well as an active LOW enable input (LE). The 74LV259 has four modes of operation as shown in the mode select table. In the addressable latch mode, data on the data line (D) is written into the addressed latch. The addressed latch will follow the data input with all non-addressed latches remaining in their previous states. In the memory mode, all latches remain in their previous states and are unaffected by the data or address inputs.

In the 3-to-8 decoding or demultiplexing mode, the addressed output follows the state of the D input with all other outputs in the LOW state. In the reset mode all outputs are LOW and unaffected by the address (A₀ to A₂) and date (D) input. When operating the 74LV259 as an addressable latch, changing more than one bit of address could impose a transient-wrong address. Therefore, this should only be done while in the memory mode. The mode select table summarizes the operations of the 74LV259.

QUICK REFERENCE DATA

GND = 0 V; $T_{amb} = 25^{\circ}C$; $t_r = t_f \le 2.5 \text{ ns}$

SYMBOL	PARAMETER	CONDITIONS	TYPICAL	UNIT
t _{PHL} /t _{PLH}	Propagation delay D, A _n to Q _n LE to Q _n MR to Q _n	$C_L = 15 \text{ pF};$ $V_{CC} = 3.3 \text{ V}$	17 16 14	ns
C _I	Input capacitance		3.5	pF
C _{PD}	Power dissipation capacitance per latch	$V_I = GND \text{ to } V_{CC}^1$	19	pF

NOTE:

ORDERING INFORMATION

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PACKAGES	TEMPERATURE RANGE	OUTSIDE NORTH AMERICA	NORTH AMERICA	PKG. DWG. #
16-Pin Plastic DIL	-40°C to +125°C	74LV259 N	74LV259 N	SOT38-4
16-Pin Plastic SO	-40°C to +125°C	74LV259 D	74LV259 D	SOT109-1
16-Pin Plastic SSOP Type II	-40°C to +125°C	74LV259 DB	74LV259 DB	SOT338-1
16-Pin Plastic TSSOP Type I	-40°C to +125°C	74LV259 PW	74LV259PW DH	SOT403-1

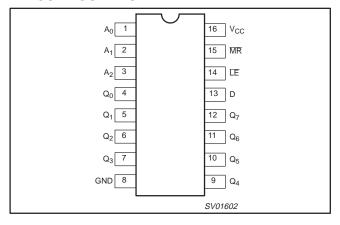
 C_{PD} is used to determine the dynamic power dissipation (P $_{D}$ in $\mu W)$ $P_D = C_{PD} \times V_{CC}^2 \times f_i + \sum (C_L \times V_{CC}^2 \times f_0)$ where: f_i = input frequency in MHz; C_L = output load capacity in pF; f_o = output frequency in MHz; V_{CC} = supply voltage in V;

 $[\]sum (C_L \times V_{CC}^2 \times f_0) = \text{sum of the outputs.}$

8-bit addressable latch

74LV259

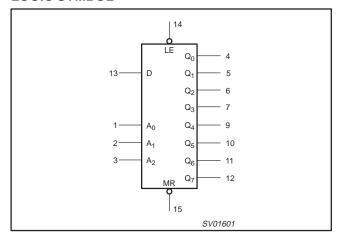
PIN CONFIGURATION



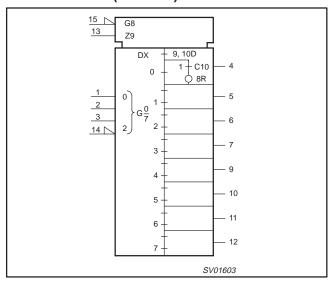
PIN DESCRIPTION

PIN NUMBER	SYMBOL	FUNCTION						
1, 2, 3	A ₀ to A ₂	Address inputs						
4, 5, 6, 7, 9, 10, 11, 12	Q ₀ to Q ₇	Latch outputs						
8	GND	Ground (0 V)						
13	D	Data input						
14	LE	Latch enable input (active LOW)						
15	MR	Conditional reset input (active LOW)						
16	V _{CC}	Positive supply voltage						

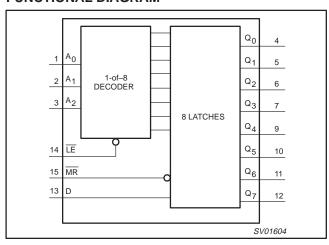
LOGIC SYMBOL



LOGIC SYMBOL (IEEE/IEC)



FUNCTIONAL DIAGRAM



MODE SELECT TABLE

LE	MR	MODE
L	Н	Addressable latch
Н	Н	Memory
L	L	Active HIGH 8-channel demultiplexer
Н	L	Reset

8-bit addressable latch

74LV259

FUNCTION TABLE

OPERATING MODES			INP	UTS						OUTI	PUTS			
OPERATING MODES	MR	LE	D	A ₀	A ₁	A ₂	Q_0	Q_1	Q ₂	Q_3	Q_4	Q ₅	Q_6	Q ₇
Master reset	L	Н	Х	Х	Х	Х	L	L	L	L	L	L	L	L
Demultiplex (active HIGH)	L	L	d	L	L	L	Q=d	L	L	L	L	L	L	L
	L	L	d	Н	L	L	L	Q=d	L	L	L	L	L	L
	L	L	d	L	Н	L	L	L	Q=d	L	L	L	L	L
	L	L	d	Н	Н	L	L	L	L	Q=d	L	L	L	L
decoder (when D = H)	L	L	d	L	L	Н	L	L	L	L	Q=d	L	L	L
(WHICH B = 11)	L	L	d	Н	L	Н	L	L	L	L	L	Q=d	L	L
	L	L	d	L	Н	Н	L	L	L	L	L	L	Q=d	L
	L	L	d	Н	Н	Н	L	L	L	L	L	L	L	Q=d
Store (do nothing)	Н	Н	Х	Х	Х	Х	q0	q1	q2	q3	q4	q5	q6	q7
	Н	L	d	L	L	L	Q=d	q1	q2	q3	q4	q5	q6	q7
	Н	L	d	Н	L	L	q0	Q=d	q2	q3	q4	q5	q6	q7
	Н	L	d	L	Н	L	q0	q1	Q=d	q3	q4	q5	q6	q7
Addressable latch	Η	L	d	Н	Н	L	q0	q1	q2	Q=d	q4	q5	q6	q7
Addressable lateri	Н	L	d	L	L	Н	q0	q1	q2	q3	Q=d	q5	q6	q7
	Н	L	d	Н	L	Н	q0	q1	q2	q3	q4	Q=d	q6	q7
	Н	L	d	L	Н	Н	q0	q1	q2	q3	q4	q5	Q=q	q7
	Н	L	d	Н	Н	Н	q0	q1	q2	q3	q4	q5	q6	Q=d

NOTES:

HIGH voltage level LOW voltage level

don't care
HIGH or LOW data one set-up time prior to the LOW-to-HIGH LE transition

lower case letters indicate the state of the referenced output established during the last cycle established during the last cycle in which it was addressed or cleared

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	CONDITIONS	MIN	TYP	MAX	UNIT
V _{CC}	DC supply voltage	1.0	3.3	3.6	V	
VI	Input voltage		0	_	V _{CC}	V
Vo	Output voltage		0	_	V _{CC}	V
T _{amb}	Operating ambient temperature range in free air	See DC and AC characteristics	-40 -40		+85 +125	°C
t _r , t _f	Input rise and fall times	$V_{CC} = 1.0V \text{ to } 2.0V$ $V_{CC} = 2.0V \text{ to } 2.7V$ $V_{CC} = 2.7V \text{ to } 3.6V$	- - -	- - -	500 200 100	ns/V

1. The LV is guaranteed to function down to V_{CC} = 1.0V (input levels GND or V_{CC}); DC characteristics are guaranteed from V_{CC} = 1.2V to V_{CC} = 5.5V.

8-bit addressable latch

74LV259

ABSOLUTE MAXIMUM RATINGS^{1, 2}

In accordance with the Absolute Maximum Rating System (IEC 134). Voltages are referenced to GND (ground = 0 V).

SYMBOL	PARAMETER	CONDITIONS	RATING	UNIT
V _{CC}	DC supply voltage		-0.5 to +4.6	V
± I _{IK}	DC input diode current	$V_{I} < -0.5 \text{ or } V_{I} > V_{CC} + 0.5V$	20	mA
± I _{OK}	DC output diode current	$V_{O} < -0.5 \text{ or } V_{O} > V_{CC} + 0.5V$	50	mA
± I _O	DC output source or sink current – standard outputs	$-0.5V < V_O < V_{CC} + 0.5V$	25	mA
±I _{GND} , ±I _{CC}	DC V _{CC} or GND current for types with – standard outputs		50	mA
T _{stg}	Storage temperature range		-65 to +150	°C
P _{TOT}	Power dissipation per package – plastic DIL – plastic mini-pack (SO) – plastic shrink mini-pack (SSOP and TSSOP)	for temperature range: -40 to +125°C above +70°C derate linearly with 12 mW/K above +70°C derate linearly with 8 mW/K above +60°C derate linearly with 5.5 mW/K	750 500 400	mW

NOTES:

DC ELECTRICAL CHARACTERISTICS

Over recommended operating conditions. Voltages are referenced to GND (ground = 0 V).

					LIMITS			
SYMBOL	PARAMETER	TEST CONDITIONS	-40)°C to +8	5°C	-40°C to	+125°C	UNIT
			MIN	TYP ¹	MAX	MIN	MAX	
		V _{CC} = 1.2 V	0.9			0.9		
V _{IH}	HIGH level Input voltage	V _{CC} = 2.0 V	1.4			1.4		٧
	l voillage	V _{CC} = 2.7 to 3.6 V	2.0			2.0		
		V _{CC} = 1.2 V			0.3		0.3	
V_{IL}	LOW level Input voltage	V _{CC} = 2.0 V			0.6		0.6	V
	· - · · · · · · · · · · · · · · · · ·	$V_{CC} = 2.7 \text{ to } 3.6 \text{ V}$			0.8		0.8	
		$V_{CC} = 1.2 \text{ V}; V_I = V_{IH} \text{ or } V_{IL}; -I_O = 100 \mu\text{A}$		1.2				
\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \	HIGH level output	$V_{CC} = 2.0 \text{ V}; V_I = V_{IH} \text{ or } V_{IL;} -I_O = 100 \mu A$	1.8	2.0		1.8		
V _{OH}	voltage; all outputs	$V_{CC} = 2.7 \text{ V}; V_I = V_{IH} \text{ or } V_{IL}; -I_O = 100 \mu\text{A}$	2.5	2.7		2.5		V
		$V_{CC} = 3.0 \text{ V}; V_I = V_{IH} \text{ or } V_{IL;} -I_O = 100 \mu A$	2.8	3.0		2.8]
V _{OH}	HIGH level output voltage; STANDARD outputs	$V_{CC} = 3.0 \text{ V}; V_I = V_{IH} \text{ or } V_{IL;} -I_O = 6\text{mA}$	2.40	2.82		2.20		V
		$V_{CC} = 1.2 \text{ V}; V_I = V_{IH} \text{ or } V_{IL}; I_O = 100 \mu\text{A}$		0				
.,	LOW level output	$V_{CC} = 2.0 \text{ V}; V_I = V_{IH} \text{ or } V_{IL}; I_O = 100 \mu\text{A}$		0	0.2		0.2	
V _{OL}	voltage; all outputs	$V_{CC} = 2.7 \text{ V; } V_{I} = V_{IH} \text{ or } V_{IL;} I_{O} = 100 \mu A$		0	0.2		0.2	1 '
		$V_{CC} = 3.0 \text{ V}; V_I = V_{IH} \text{ or } V_{IL;} I_O = 100 \mu\text{A}$		0	0.2		0.2	1
V _{OL}	LOW level output voltage; STANDARD outputs	$V_{CC} = 3.0 \text{ V}; V_I = V_{IH} \text{ or } V_{IL;} I_O = 6\text{mA}$		0.25	0.40		0.50	V

Stresses beyond those listed may cause permanent damage to the device. These are stress ratings only and functional operation of the
device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to
absolute-maximum-rated conditions for extended periods may affect device reliability.

^{2.} The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

8-bit addressable latch

74LV259

DC ELECTRICAL CHARACTERISTICS (Continued)
Over recommended operating conditions. Voltages are referenced to GND (ground = 0 V).

					LIMITS			
SYMBOL	PARAMETER	TEST CONDITIONS	-40	°C to +85	5°C	-40°C to	UNIT	
			MIN	TYP ¹	MAX	MIN	MAX	
II	Input leakage current	$V_{CC} = 3.6 \text{ V}; V_I = V_{CC} \text{ or GND}$			1.0		1.0	μА
Icc	Quiescent supply current; MSI	$V_{CC} = 3.6 \text{ V}; V_{I} = V_{CC} \text{ or GND}; I_{O} = 0$			20.0		160	μА
Δl _{CC}	Additional quiescent supply current per input	V_{CC} = 2.7 V to 3.6 V; V_{I} = V_{CC} – 0.6 V			500		850	μА

NOTE:

AC CHARACTERISTICS

 $\label{eq:gnd} \text{GND} = \text{0V; } t_{\text{r}} = t_{\text{f}} \leq \text{2.5ns; } C_{\text{L}} = \text{50pF; } R_{\text{L}} = \text{1K}\Omega$

			CONDITION			LIMITS			
SYMBOL	PARAMETER	WAVEFORM	CONDITION	_	40 to +85 °	C	-40 to	+125 °C	UNIT
			V _{CC} (V)	MIN	TYP ¹	MAX	MIN	MAX	
			1.2		105				
	Propagation delay	Figure 2	2.0		36	49		61	
t _{PHL} /t _{PLH}	D to Q _n	Figure 2	2.7	T	26	36		45	ns
			3.0 to 3.6		20 ²	29		36	
			1.2		105				
	Propagation delay	Figure 2	2.0		36	49		61	
t _{PHL} /t _{PLH}	A_n to Q_n Figure		2.7		26	36		45	ns
		ΙГ	3.0 to 3.6		20 ²	29		36	
			1.2		100				
	Propagation delay	Figure 4	2.0	T	34	48		60	
t _{PHL} /t _{PLH}	LE to Q _n	Figure 1	2.7	T	25	35		44	ns
			3.0 to 3.6		19 ²	28		35	
			1.2		90				
	Propagation delay	Figure 4	2.0		31	43		53	
t _{PHL}	MR to Q _n	Figure 4	2.7		23	31		39	ns
		ΙГ	3.0 to 3.6		17 ²	25		31	
			2.0	34	10		41		
t_{w}	LE pulse width HIGH or LOW	Figure 1	2.7	25	8		30		ns
			3.0 to 3.6	20	6 ²		24		
			2.0	34	10		41		
t_w	MR pulse width LOW	Figure 4	2.7	25	8		30		ns
			3.0 to 3.6	20	6 ²		24		
			1.2		35				
	Set-up time	Figure 5 and 6	2.0	24	12		29		
t _{su}	D _, A _n to LE	Figure 5 and 6	2.7	18	9		21		ns
		<u> </u>	3.0 to 3.6	14	7 ²		17		
			1.2		-30				
.	Hold time	Figure 5	2.0	5	-10		5		no
t _h	D to LE	Figure 5	2.7	5	-8		5		ns
		i l	3.0 to 3.6	5	-6 ²		5		

^{1.} All typical values are measured at $T_{amb} = 25$ °C.

8-bit addressable latch

74LV259

AC CHARACTERISTICS (Continued)

GND = 0V; t_r = t_f \leq 2.5ns; C_L = 50pF; R_L = 1K Ω

SYMBOL	PARAMETER	WAVEFORM	CONDITION	_	40 to +85 °	С	-40 to -	+125 °C	UNIT
	TANAMILTEN	WAVEI OKW	V _{CC} (V) MIN TYP		TYP ¹	MAX	MIN	MAX	J
			1.2		-20				
	Hold time A _n to LE	Figure 6	2.0	5	-7		5		
t _h			2.7	5	- 5		5		ns
			3.0 to 3.6	5	-4 ²		5		

NOTES:

- 1. Unless otherwise stated, all typical values are measured at T_{amb} = 25°C 2. Typical values are measured at V_{CC} = 3.3 V.

AC WAVEFORMS

 $V_M = 1.5 \text{ V at } V_{CC} \ge 2.7 \text{ V and } \le 3.6 \text{V};$

 $V_{M} = 0.5 \times V_{CC}$ at $V_{CC} < 2.7 \ V$ and $\geq 4.5 \ V.$

V_{OL} and V_{OH} are the typical output voltage drop that occur with the output load.

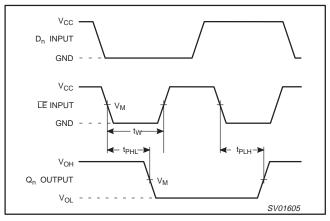


Figure 1. Enable input (LE) to output (Qn) propagation delays and the enable input pulse width.

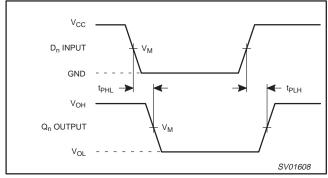


Figure 2. Data input (D) to output (Qn) propagation delays.

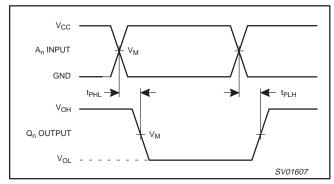


Figure 3. Address inputs (A_n) to output (Q_n) propagation delays.

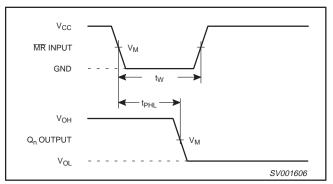


Figure 4. Conditional reset input (MR) to output (Qn) propagation delays.

8-bit addressable latch

74LV259

AC WAVEFORMS (Continued)

$$\begin{split} &V_M=1.5~V~at~V_{CC}\geq 2.7~V~and \leq 3.6V;\\ &V_M=0.5\times V_{CC}~at~V_{CC}<2.7~V~and \geq 4.5~V. \end{split}$$

 \mbox{V}_{OL} and \mbox{V}_{OH} are the typical output voltage drop that occur with the output load.

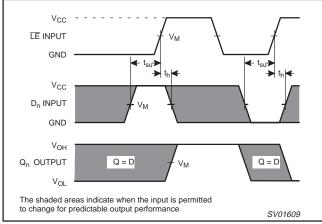


Figure 5. Data set-up and hold times for D input to $\overline{\text{LE}}$ input.

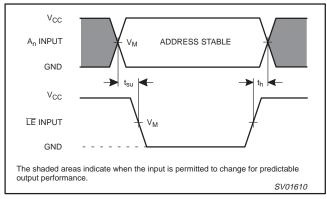


Figure 6. Address set-up and hold times for A_n inputs to \overline{LE} input.

TEST CIRCUIT

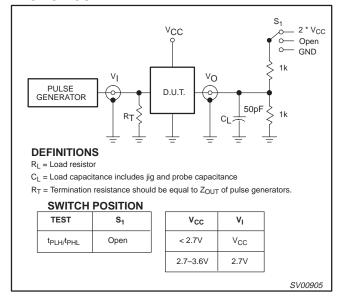


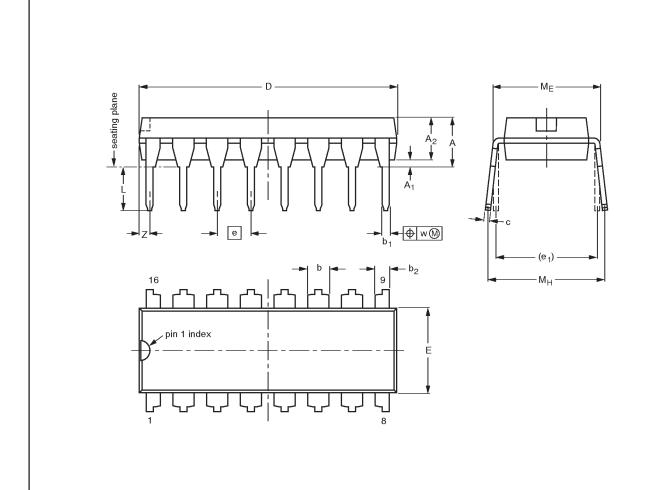
Figure 7. Load circuitry for switching times.

8-bit addressable latch

74LV259

DIP16: plastic dual in-line package; 16 leads (300 mil)

SOT38-4



DIMENSIONS (inch dimensions are derived from the original mm dimensions)

UNIT	A max.	A ₁ min.	A ₂ max.	b	b ₁	b ₂	C	D ⁽¹⁾	E ⁽¹⁾	е	e ₁	L	ME	M _H	w	Z ⁽¹⁾ max.
mm	4.2	0.51	3.2	1.73 1.30	0.53 0.38	1.25 0.85	0.36 0.23	19.50 18.55	6.48 6.20	2.54	7.62	3.60 3.05	8.25 7.80	10.0 8.3	0.254	0.76
inches	0.17	0.020	0.13	0.068 0.051	0.021 0.015	0.049 0.033	0.014 0.009	0.77 0.73	0.26 0.24	0.10	0.30	0.14 0.12	0.32 0.31	0.39 0.33	0.01	0.030

scale

10 mm

Note

1. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

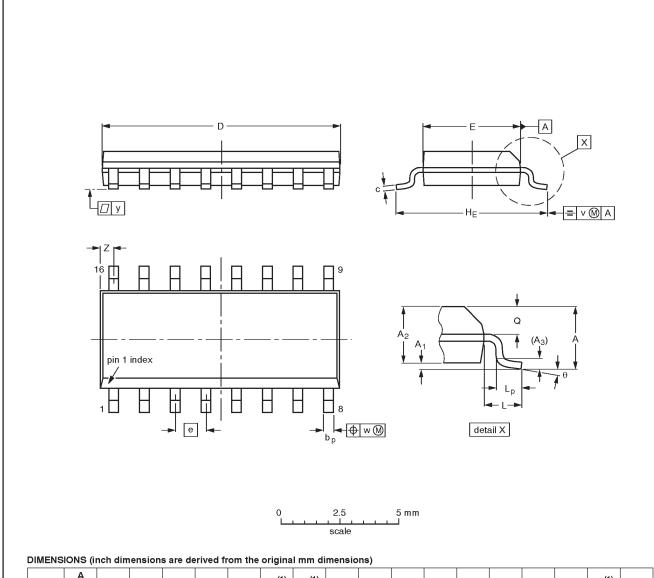
OUTLINE		REFER	EUROPEAN	ISSUE DATE		
VERSION	IEC	JEDEC	EIAJ		PROJECTION	ISSUE DATE
SOT38-4					□ •	92-11-17 95-01-14

8-bit addressable latch

74LV259

SO16: plastic small outline package; 16 leads; body width 3.9 mm

SOT109-1



UNIT	A max.	Α1	A ₂	А3	bр	С	D ⁽¹⁾	E ⁽¹⁾	е	HE	L	Lp	Q	v	w	у	Z ⁽¹⁾	θ
mm	1.75	0.25 0.10	1.45 1.25	0.25	0.49 0.36	0.25 0.19	10.0 9.8	4.0 3.8	1.27	6.2 5.8	1.05	1.0 0.4	0.7 0.6	0.25	0.25	0.1	0.7 0.3	8°
inches	0.069	0.0098 0.0039		0.01	0.019 0.014	0.0098 0.0075	0.39 0.38	0.16 0.15	0.050	0.24 0.23	0.041	0.039 0.016		0.01	0.01	0.004	0.028 0.012	0°

Note

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

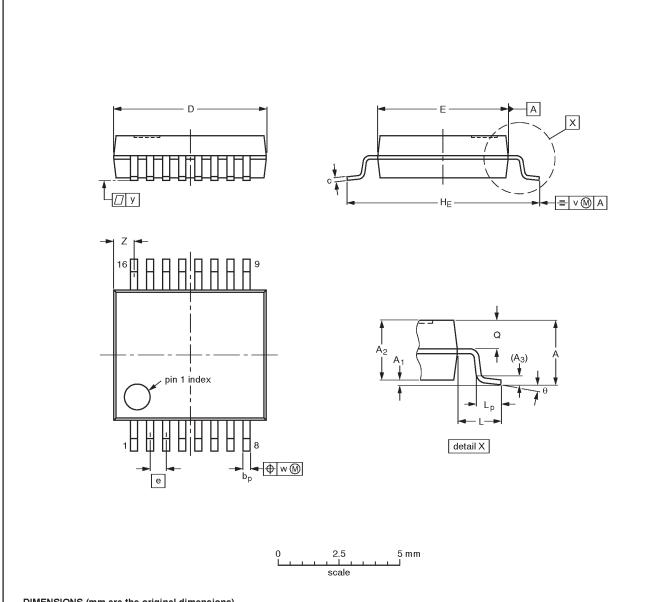
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VERSION	IEC	JEDEC	EIAJ		PROJECTION		
SOT109-1	076E07\$	MS-012AC				91-08-13 95-01-23	

8-bit addressable latch

74LV259

SSOP16: plastic shrink small outline package; 16 leads; body width 5.3 mm

SOT338-1



DIMENSIONS (mm are the original dimensions)

UNIT	A max.	A ₁	A ₂	A ₃	рb	c	D ⁽¹⁾	E ⁽¹⁾	е	HE	L	Lp	Ø	v	w	у	Z ⁽¹⁾	θ
mm	2.0	0.21 0.05	1.80 1.65	0.25	0.38 0.25	0.20 0.09	6.4 6.0	5.4 5.2	0.65	7.9 7.6	1.25	1.03 0.63	0.9 0.7	0.2	0.13	0.1	1.00 0.55	8° 0°

Note

1. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

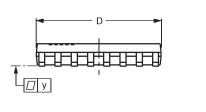
OUTLINE		REFER	EUROPEAN	ISSUE DATE		
VERSION	VERSION IEC		EIAJ	PROJECTION		ISSUE DATE
SOT338-1		MO-150AC				94-01-14 95-02-04

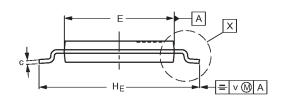
8-bit addressable latch

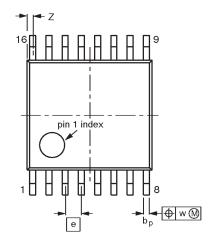
74LV259

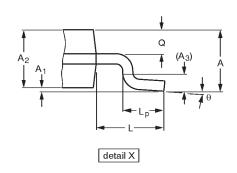
TSSOP16: plastic thin shrink small outline package; 16 leads; body width 4.4 mm

SOT403-1











DIMENSIONS (mm are the original dimensions)

UNIT	A max.	Α1	A ₂	А3	bp	С	D ⁽¹⁾	E ⁽²⁾	е	HE	L	Lp	Ø	v	w	у	Z ⁽¹⁾	θ
mm	1.10	0.15 0.05	0.95 0.80	0.25	0.30 0.19	0.2 0.1	5.1 4.9	4.5 4.3	0.65	6.6 6.2	1.0	0.75 0.50	0.4 0.3	0.2	0.13	0.1	0.40 0.06	8° 0°

Notes

- 1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.
- 2. Plastic interlead protrusions of 0.25 mm maximum per side are not included.

OUTLINE		EUROPEAN	ISSUE DATE			
VERSION	IEC	JEDEC	EIAJ	PROJECTION	1330E DATE	
SOT403-1		MO-153			-94-07-12- 95-04-04	

8-bit addressable latch

74LV259

NOTES

8-bit addressable latch

74LV259

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Data Sheet Identification	Product Status	Definition							
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